



功率半导体芯片 | Power Semiconductor Chips



» 晶闸管芯片 | Thyristor Chips

标准:

- 每片芯片全部在 T_{JM} 下测试，严格禁止抽检
- 产品参数一致性极佳

Standard:

- Every chips are tested at T_{JM} , random inspections are strictly prohibited.
- Excellent consistency of the chips' parameters

特点:

- 通态压降低
- 具有很强的抗热疲劳能力
- 阴极铝层厚度 10 微米以上
- 台面双层保护

Features:

- Low forward voltage
- Strong thermal fatigue resistance
- The thickness of cathode aluminum layer is above $10 \mu m$
- Double layer protections on mesa



| 芯片直径 Diameter | 芯片厚度 Thickness | 电压范围 Voltage | 门极直径 Gate Dia. | 阴极内径 Cathode Inner Dia. | 阴极外径 Cathode Out Dia. | 结温 T_{jm} |
|------------------|-------------------|-----------------|-------------------|----------------------------|--------------------------|----------------|
| mm | mm | V | mm | mm | mm | °C |
| 25.4 | 1.5±0.1 | ≤2000 | 2.5 | 5.6 | 20.3 | 125 |
| | 1.6~1.8 | 2200~3500 | 2.6 | 5.6 | 15.9 | 125 |
| 29.72 | 2±0.1 | ≤2000 | 3.3 | 7.7 | 24.5 | 125 |
| 32 | 2±0.1 | ≤2000 | 3.3 | 7.7 | 26.1 | 125 |
| 35 | 2±0.1 | ≤2000 | 3.8 | 7.6 | 29.1 | 125 |
| | 2.1~2.4 | 2200~4200 | 3.8 | 7.6 | 24.9 | 125 |
| 38.1 | 2±0.1 | ≤2000 | 3.3 | 7.7 | 32.8 | 125 |
| 40 | 2±0.1 | ≤2000 | 3.3 | 7.7 | 33.9 | 125 |
| | 2.1~2.4 | 2200~4200 | 3.5 | 8.1 | 30.7 | 125 |
| 45 | 2.3±0.1 | ≤2000 | 3.6 | 8.8 | 37.9 | 125 |
| 50.8 | 2.5±0.1 | ≤2000 | 3.6 | 8.8 | 43.3 | 125 |
| | 2.6~2.9 | 2200~4200 | 3.8 | 8.6 | 41.5 | 125 |
| | 2.6~2.8 | 2600~3500 | 3.3 | 7 | 41.5 | 125 |
| 55 | 2.5±0.1 | ≤2000 | 3.3 | 8.8 | 47.3 | 125 |
| | 2.5~2.9 | ≤4200 | 3.8 | 8.6 | 45.7 | 125 |
| 60 | 2.6~3.0 | ≤4200 | 3.8 | 8.6 | 49.8 | 125 |
| 63.5 | 2.7~3.1 | ≤4200 | 3.8 | 8.6 | 53.4 | 125 |
| 70 | 3.0~3.4 | ≤4200 | 5.2 | 10.1 | 59.9 | 125 |
| 76 | 3.5~4.1 | ≤4800 | 5.2 | 10.1 | 65.1 | 125 |
| 89 | 4~4.4 | ≤4200 | 5.2 | 10.1 | 77.7 | 125 |
| 99 | 4.5~4.8 | ≤3500 | 5.2 | 10.1 | 87.7 | 125 |